Thursday, March 20, 2014
POSTER SESSION: GENESIS
6:00 p.m.  Town Center Exhibit Area

Gonzalez C. P.  Goreva Y. S.  Burnett D. S.  Woolum D.  Jurewicz A. J.  et al.  POSTER LOCATION #544
Cleanliness assessment of Genesis solar wind sample 60341 using optical imagery and ToF-SIMS mapping is monitored throughout several cleaning processes.

Rieck K. D.  Jurewicz A. J. G.  Burnett D. S.  Hervig R. L.  POSTER LOCATION #545
Internally Standardized Measurements of Solar Wind Sodium and Potassium in Genesis Diamond-Like Carbon Collectors [#1758]
We present standardized measurements of bulk solar wind Na and 39K abundances in Genesis Si and diamond-on-Si wafers using backside depth profiling by SIMS.

Goreva Y. S.  Gonzalez C. P.  Kuhlman K. R.  Burnett D. S.  Woolum D.  et al.  POSTER LOCATION #546
Genesis Solar Wind Collector Cleaning Assessment: 60336 Sample Case Study [#2245]
As a part of Genesis Cleaning Study effort, here we present results for sample 60336, subjected to extensive study via various techniques.

Kuhlman K. R.  Schmeling M.  Gonzalez C. P.  Allton J. H.  Burnett D. S.  POSTER LOCATION #547
Cellulose Acetate Replica Cleaning Study of Genesis Non-Flight Sample 3CZ00327 [#2030]
Cellulose acetate replica cleaning of Genesis samples is validated using control sample 3CZ00327. Residues are removed using hot xylene and acetone.

Goreva Y. S.  Humayun M.  Burnett D. S.  Jurewicz A. J.  Gonzalez C. P.  POSTER LOCATION #548
TOF-SIMS Investigation of the Effectiveness of Acid-Cleaning Procedures for Genesis Solar Wind Collectors [#2586]
In this work we present results of chemical cleaning of 6Li-implanted Genesis flight samples.

Westphal A. J.  Oglitore R. C.  Huss G. R.  Nakashima K.  Olinger C.  POSTER LOCATION #549
Mg Profile Correction in Genesis Si Collectors Using Rastered Ion Imaging [#2671]
We present a backside-profiling SIMS technique with imaging, which allows pixel-by-pixel depth correction, and present results for solar wind Mg in Genesis Si.

Gonzalez C. P.  Burkett P. J.  Rodriguez M. C.  Allton J. H.  POSTER LOCATION #550
Investigation of Backside Textures for Genesis Solar Wind Silicon Collectors [#2727]
Visual backside textures of Genesis silicon solar wind collectors were investigated as a potential way to distinguish silicon variety and vendor source.

Veryovkin I. V.  Zinovev A. V.  Tripa C. E.  Burnett D. S.  POSTER LOCATION #551
Depth Profiling of Genesis Diamond-on-Silicon Collectors: Direct Comparison Between Frontside and Backside Approaches [#2795]
We present a direct comparison between frontside and backside profiling applied to measure elemental abundances of Mg in diamond-on-Si Genesis samples.

Heber V. S.  McKeegan K. D.  Smith S.  Jurewicz A. J. G.  Olinger C.  et al.  POSTER LOCATION #552
Accurate Analysis of Shallow Solar Wind Ion Implants by SIMS Backside Depth Profiling [#1203]
Our technique is capable of analyzing nearly complete depth distributions of many solar-wind elements even in the presence of high levels of surface contamination.
Wimmer-Schweingruber R. F. Berger L. Köten M. Bochsler P. Gloeckler G.  
**POSTER LOCATION #553**  
*The 13C/12C Isotopic Ratio in the Solar Wind* [#1114]  
We present the long-term slow solar wind carbon isotopic ratio $^{12}$C/$^{13}$C ~ 97 ± 10 as derived from ACE/SWICS. The value is consistent with the terrestrial one.

Mandt K. E. Mousis O. Lunine J. I. Gautier D.  
**POSTER LOCATION #554**  
*Improved Constraints on the Nitrogen Isotopes in the Protosolar Nebula: Implications for the Source of the Earth’s Nitrogen* [#1955]  
Measurements of $^{14}$N/$^{15}$N in the solar system show two primordial inventories of nitrogen: N$_2$ with a ratio of ~435 and NH$_3$ and HCN with a ratio of ~150.

Heber V. S. McKeegan K. D. Bochsler P. Duprat J. Burnett D. S.  
**POSTER LOCATION #555**  
*The Elemental Composition of Solar Wind with Implications for Fractionation Processes During Solar Wind Formation* [#2117]  
We present bulk SW and SW regime elemental abundances measured in Genesis collectors comprising a wide range of masses and ionization properties.

Schmeling M. Hwang E. Choi Y. Eng P. J. Stubbs J. E. et al.  
**POSTER LOCATION #556**  
*Analysis of Genesis Sample 60234 by Laboratory Total Reflection X-Ray Fluorescence Spectrometry and Synchrotron Grazing Incidence X-Ray Fluorescence* [#2119]  
Genesis sample 60234 was characterized by laboratory TXRF and synchrotron GI-XRF. Surface contaminants were identified as well as elements within the bulk.